

FORM PTO-1449 SAMUELS, GAUTHIER & STEVENS LLP
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MIT.10086
 ATTORNEY DOCKET NO.

10/733,977
 SERIAL NO.

APPLICANT: Kimerling et al.
 FILING DATE: 12/11/2003

GROUP: 2883

EXAMINER: ~~Unknown~~

Derek Dupuis

**INFORMATION DISCLOSURE
 STATEMENT BY APPLICANT**

JUL 09 2004

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	TRADEMARK OFFICE	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
DJD	AA	5,107,316	04/21/1992	Jelley et al.			12/28/1989
	AB						
	AC						

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
DJD	AD	62011810	01/20/1987	JP			YES (Abstract Only)
DJD	AE	923335	10/23/1982	SU			YES (Abstract Only)
	AF						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER INITIAL		
DJD	AG	"Development and Application of flux-paste for laser welding of aluminum alloys," Cretteur et al. <i>Welding International</i> . 2000.
DJD	AH	"Theoretical study on the coupling of two-dimensional Gaussian beam to a dielectric slab waveguide," Nishimura et al. <i>Transactions of the Institute of Electronics and Communication Engineers of Japan</i> . May 1984.
DJD	AI	"Fresnel-like behavior of guided waves," Shen et al. <i>Journal of Optical Society of America</i> . November 1987.
DJD	AJ	"Ultrafast photon drag detector for intersubband spectroscopy," Sigg et al. <i>Superlattices and Microstructures</i> . 1996. Vol. 19, No. 2.
DJD	AK	"Critical-Incidence Coupling to intersubband Excitations," Keilmann et al. <i>Solid State Communications</i> . 1994. Vol. 92, No. 3.
DJD	AL	"Efficient high-speed near-infrared Ge photodetectors integrated on Si Substrates," Colace et al. <i>Applied Physics Letters</i> . 2000. Vol. 76, No. 10.
DJD	AM	"Optoelectronic Conversion through 850nm Band Single Mode Si ₃ N ₄ Photonic Waveguides for Si-On-Chip Integration," Matsuura et al. <i>Device Research Conference, Conference Proceedings</i> . Santa Barbara, CA. June 2002.
DJD	AN	"Near and mid infrared silicon/germanium based photodetection," Presting. <i>Thin Solid Films</i> . 1998. Vol. 321.

EXAMINER *DL 2 d*

DATE CONSIDERED *9-15-2004*

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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~~Unknown~~ 10/7339 77
 SERIAL NO.

**INFORMATION DISCLOSURE
 STATEMENT BY APPLICANT**

APPLICANT: Kimerling et al.
 FILING DATE: ~~Hanover~~
 12/11/2003

GROUP: ~~Unknown~~ 2883
 EXAMINER: ~~Unknown~~
 Derek Dupuis

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AJ						
	AK						
	AL						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER INITIAL		
DLD	AM	"FDTD Analysis of a Polarization Conversion Waveguide with a Single Sloped Sidewall," Yamauchi et al. <i>Optical Society of America</i> . June 2003.
	AN	
	AO	

EXAMINER *DL 2. J.*

DATE CONSIDERED *9-15-2004*

EXAMINER:	Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and note considered. Include copy of this form with next communication to applicant.
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